



PATENT APPLICATION *1K*  
*AP*

IN THE U.S. PATENT AND TRADEMARK OFFICE

May 14, 2008

Applicants : Yoshio KAJIYA et al  
For : METHOD OF PRODUCING CATHODE MATERIAL FOR  
LITHIUM SECONDARY CELL  
Serial No. : 10/521 370 Group: 1795  
Confirmation No.: 2268  
Filed : January 12, 2005 Examiner: Echelmeyer  
International Application No.: PCT/JP2003/002027  
International Filing Date : February 25, 2003  
Atty. Docket No.: 4402.P0666US

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

**NOTICE OF APPEAL FROM THE PRIMARY EXAMINER  
TO THE BOARD OF APPEALS**

Sir:

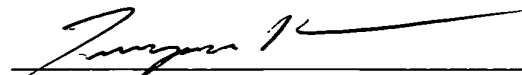
Applicant hereby appeals to the Board of Appeals from the decision mailed November 14, 2007 of the Primary Examiner finally rejecting Claims 1-8.

(Please see following page.)

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**CERTIFICATE OF MAILING**

I hereby certify that this correspondence is being deposited with the United States Postal Service as first class mail in an envelope addressed to: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450, on May 14, 2008.

Respectfully submitted,

  
Terryence F. Chapman

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The item(s) checked below are appropriate:

☒ A Petition and fee for extension accompany this Notice.

☒ Appeal fee:

☒ \$510.00 (large entity).

☐ \$255.00 (small entity).

Statement(s) re small entity status:

☐ Attached.

☐ Previously filed.

☒ A check for \$1,560.00 is enclosed to cover fees.

☐ Please charge the Appeal Fee of \$\_\_\_\_\_ to Deposit Account 06-1382. A duplicate copy of this sheet is enclosed.

☒ The Commissioner is hereby authorized to charge any additional fees required by this paper or to credit any overpayment to Deposit Account No. 06-1382. A duplicate copy of this sheet is enclosed.

☒ An acknowledgement Postal Card is enclosed.

Respectfully submitted,

IN DUPLICATE

  
Terryence F. Chapman

TFC/smd

FLYNN, THIEL, BOUTELL  
& TANIS, P.C.  
2026 Rambling Road  
Kalamazoo, MI 49008-1631  
Phone: (269) 381-1156  
Fax: (269) 381-5465

David G. Boutell  
Terryence F. Chapman  
Mark L. Maki  
Liane L. Churney  
John A. Waters  
Brian R. Tumm  
Donald J. Wallace  
Stephen C. Holwerda  
Dale H. Thiel  
Sidney B. Williams, Jr.  
Heon Jekal  
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Reg. No. 36 328  
Reg. No. 43 977  
Reg. No. 57 391  
Reg. No. 24 323  
Reg. No. 24 949  
Reg. No. L0379\*

Encl: Listed Above

150.09/07